FAIRCHILD

SEMICONDUCTOR

June 2000 Revised October 2006

FSTUD16211 24-Bit Bus Switch with –2V Undershoot Protection and Level Shifting

General Description

The Fairchild Switch FSTUD16211 provides 24-bits of high-speed CMOS TTL-compatible bus switching. The low on resistance of the switch allows inputs to be connected to outputs without adding propagation delay or generating additional ground bounce noise. A diode to V_{CC} has been integrated into the circuit to allow for level shifting between 5V inputs and 3.3V outputs.

The device is organized as a 12-bit or 24-bit bus switch. When \overline{OE}_1 is LOW, the switch is ON and Port 1A is connected to Port 1B. When \overline{OE}_2 is LOW, Port 2A is connected to Port 2B. When $\overline{OE}_{1/2}$ is HIGH, a high impedance state exists between the A and B Ports. The A and B Ports have "undershoot hardened" circuit protection to support an extended range to 2.0V below ground. Fairchild's integrated Undershoot Hardened Circuit (UHC®) senses undershoot at the I/O's, and responds by preventing voltage differentials from developing and turning on the switch.

Features

- Undershoot hardened to -2V (A and B Ports)
- Voltage level shifting
- \blacksquare 4 Ω switch connection between two ports
- Minimal propagation delay through the switch
- Low I_{CC}
- Zero bounce in flow-through mode
- Control inputs compatible with TTL level
- See Applications Note AN-5008 for details

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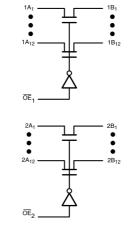
Also packaged in plastic Fine-Pitch Ball Grid Array (FBGA) (Preliminary) FSTUD16211 24-Bit Bus Switch with –2V Undershoot Protection and Level Shifting

Ordering Code:

Order Number	Package Number	Package Description
FSTUD16211GX (Note 1)		54-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide [TAPE and REEL]
FSTUD16211MTD	MTD56	56-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide

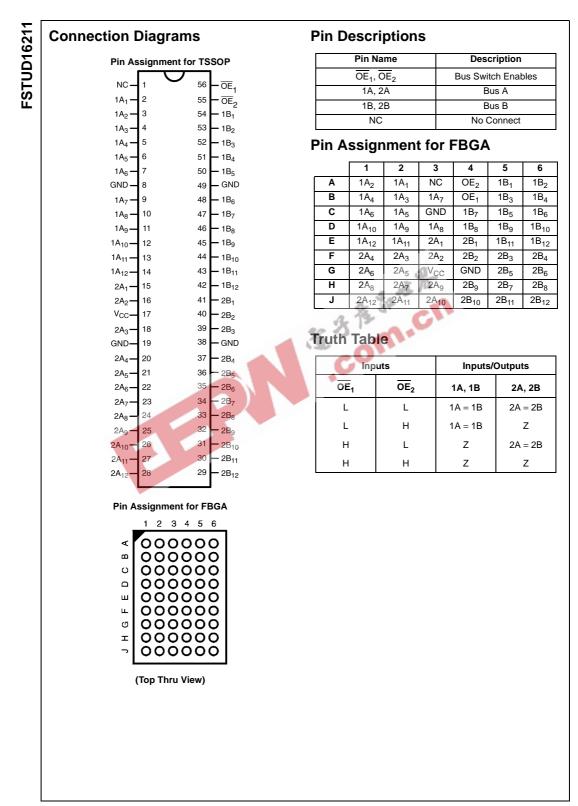
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code. Note 1: BGA package available in Tape and Reel only.

Logic Diagram



UHC® is a registered trademark of Fairchild Semiconductor Corporation.

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Absolute Maximum Ratings(Note 2)

Supply Voltage (V _{CC})	-0.5V to +7.0V
DC Switch Voltage (V _S) (Note 3)	-2.0V to +7.0V
DC Input Control Pin Voltage (VIN)(Note 4)	-0.5V to +7.0V
DC Input Diode Current (I_{IK}) $V_{IN} < 0V$	–50 mA
DC Output (I _{OUT})	128 mA
DC V _{CC} /GND Current (I _{CC} /I _{GND})	+/- 100 mA
Storage Temperature Range (T _{STG})	–65°C to +150 °C

Recommended Operating Conditions (Note 5)

Power Supply Operating (V _{CC)}	4.5V to 5.5V
Input Voltage (V _{IN})	0V to 5.5V
Output Voltage (V _{OUT})	0V to 5.5V
Input Rise and Fall Time (t_r, t_f)	
Switch Control Input	0 ns/V to 5 ns/V
Switch I/O	0 ns/V to DC
Free Air Operating Temperature (T _A)	-40 °C to +85 °C

Note 2: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum rating. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 3: V_S is the voltage observed/applied at either A or B Ports across the switch.

Note 4: The input and output negative voltage ratings may be exceeded if

Note 4: The input and output negative voltage ratings may be exceeded if the input and output diode current ratings are observed. Note 5: Unused control inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

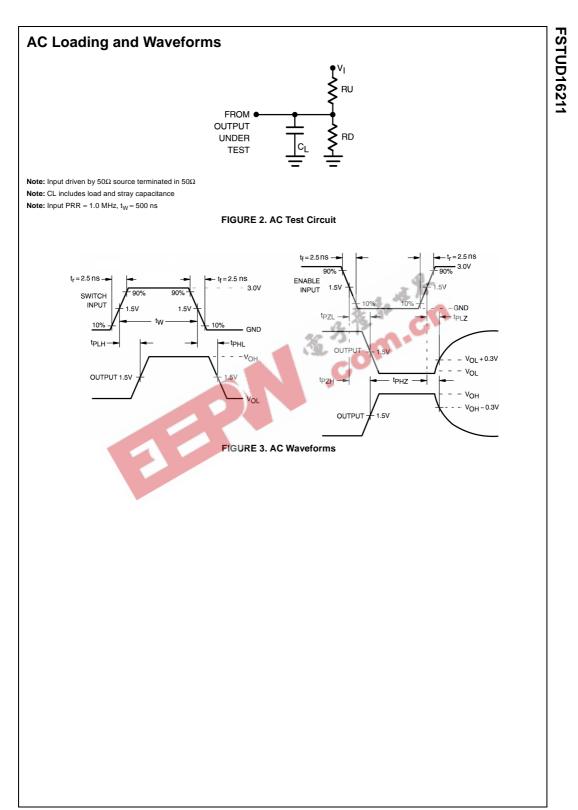
Symbol	Parameter	V _{CC} (V)	T _A = Min	= -40 °C to +8 Typ (Note 6)	85 °C Max	Units	Conditions
V _{IK}	Clamp Diode Voltage	4.5			-1.2	V	I _{IN} = -18 mA
VIH	HIGH Level Input Voltage	4.5-5.5	2.0			V	
VIL	LOW Level Input Voltage	4.5-5.5			0.8	V	
V _{OH}	HIGH Level	4.5-5.5		See Figure 4		V	
l _l	Input Leakage Current	5.5			±1.0	μΑ	$0 \le V_{IN} \le 5.5V$
		0			10	μΑ	V _{IN} = 5.5V
l _{oz}	OFF-STATE Leakage Current	5.5			±1.0	μΑ	$0 \le A, B \le V_{CC}$
R _{ON}	Switch On Resistance	4.5		4	7	Ω	$V_{IN} = 0V, I_{IN} = 64 \text{ mA}$
	(Note 7)	4.5		4	7	Ω	$V_{IN} = 0V, I_{IN} = 30 \text{ mA}$
		4.5		35	50	Ω	$V_{IN} = 2.4V, I_{IN} = 15 \text{ mA}$
Icc	Quiescent Supply Current	5.5			1.5	mA	$OE_1 = OE_2 = GND$ $V_{IN} = V_{CC}$ or GND, $I_{OUT} = 0$
		0.0			10	μΑ	$\begin{aligned} &OE_1 = OE_2 = V_{CC} \\ &V_{IN} = V_{CC} \text{ or } GND, \ I_{OUT} = 0 \end{aligned}$
ΔI_{CC}	Increase in I _{CC} per Input	5.5			2.5	mA	One Input at 3.4V Other Inputs at V _{CC} or GND
V _{IKU}	Voltage Undershoot	5.5			-2.0	V	$\frac{0.0 \text{ mA} \ge I_{\text{IN}} \ge -50 \text{ mA}}{\overline{\text{OE}}_{1, 2} = 5.5 \text{V}}$

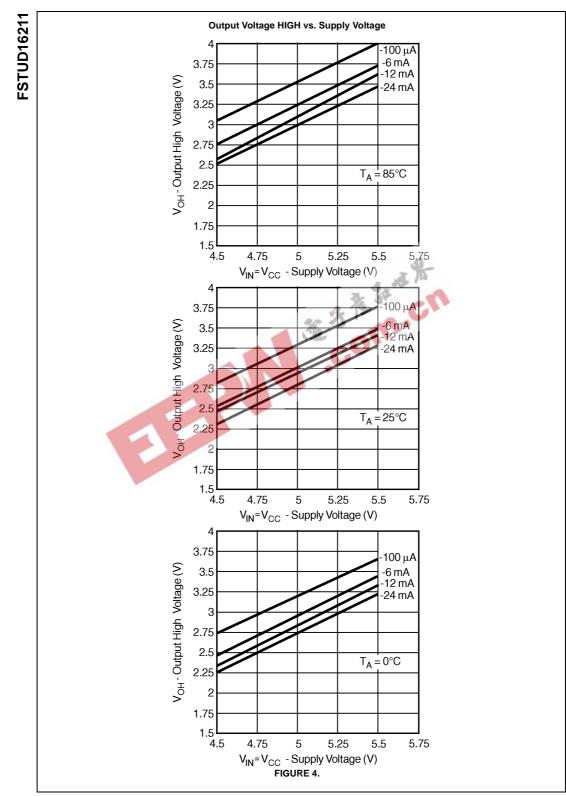
Note 6: Typical values are at V_{CC} = 5.0V and $T_{A}\text{=}+25^{\circ}\text{C}$

Note 7: Measured by the voltage drop between A and B pins at the indicated current through the switch. On Resistance is determined by the lower of the voltages on the two (A or B) pins.

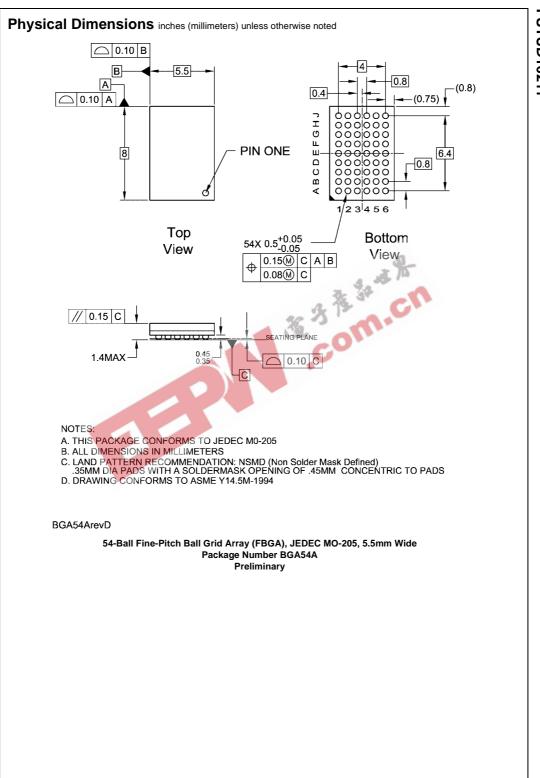
Symbol		$C_L = 50 pF, RL$	C to +85 °C, U = RD = 500Ω				Figu
	Parameter	V _{CC} = 4.	.5 – 5.5V	Units	;	Conditions	No
		Min	Max				
PHL, t _{PLH}	Propagation Delay Bus to Bus (Note 8)		0.25	ns	V _I = OPEN		Figur 2, 3
_{PZH} , t _{PZL}	Output Enable Time	1.5	5.5	ns	$V_I = 7V$ for	t _{PZL}	Figur
					V _I = OPEN	. = :	2, 3
PHZ, ^t PLZ	Output Disable Time	1.5	6.5	ns	$V_I = 7V$ for $V_I = OPEN$		Figu 2, 3
Capa	of the switch and the 50pF load capa		· · ·			-	
Symbol	Parameter	Тур	Ma	ax	Units	Condition	s
C _{IN}	Control pin Input Capacitance	3.5			pF	$V_{CC} = 5.0V$	
CI/O OFF	Input/Output Capacitance "OFF = +25°C, f = 1 MHz, Capacitance is cl		sted		pF	V _{CC} = 5.0V, Switch OF	F
	rshoot Characteri			<u>x</u>	ST IS IN	0	
Symbol	Parameter	Min	Тур	Max		Conditio	
Voutu	Output Voltage During Undersho is test is intended to characterize the	oot 2.5	V _{OH} - 0.3	R ₁	V	Figure 7	1
V _{OUTU} Note 10: Th	Output Voltage During Undersho is test is intended to characterize the	2.5 e device's protective car 5002 VIN	V _{OH} – 0.3 pabilities by maint	R ₁	V ut signal integrity o VTR1 UTU)	Figure 7	1
VOUTU Note 10: Th undershoot	Output Voltage During Undersho is test is intended to characterize the event.	Doot 2.5 e device's protective car 50(3) VIN	V _{OH} -0.3 pabilities by maint V _{CC} D.U.T. FIGURE 1.		UTU)	Figure 4	1
VOUTU Note 10: Th undershoot	Output Voltage During Undersho is test is intended to characterize the event. e Test Conditions Parameter Value	Doot 2.5 e device's protective car 5000 VIN	V _{OH} -0.3 pabilities by maint V _{CC} D.U.T. FIGURE 1.		UTU)	Figure 7	1
VOUTU Note 10: Th undershoot	Output Voltage During Undersho is test is intended to characterize the event. e Test Conditions Parameter Value VIN see Waveform	Doot 2.5 e device's protective car 50(3) VIN	V _{OH} -0.3 pabilities by maint V _{CC} D.U.T. FIGURE 1.		UTU)	Figure 4	1
VOUTU Note 10: Th undershoot	Output Voltage During Undersho is test is intended to characterize the event. etert etert	Doot 2.5 e device's protective car 50(3) VIN	V _{OH} -0.3 pabilities by maint V _{CC} D.U.T. FIGURE 1.		U U U U U U U U U U U U U U	Figure 4	1
VOUTU Note 10: Th undershoot	Output Voltage During Undersho is test is intended to characterize the event. etest Econditions Parameter Value V _{IN} see Waveform R ₁ = R ₂ 100K	bot 2.5 e device's protective car 50(2) VIN VIN	V _{OH} -0.3 pabilities by maint V _{CC} D.U.T. FIGURE 1.		U U U U U U U U U U U U U U	Figure 4	1

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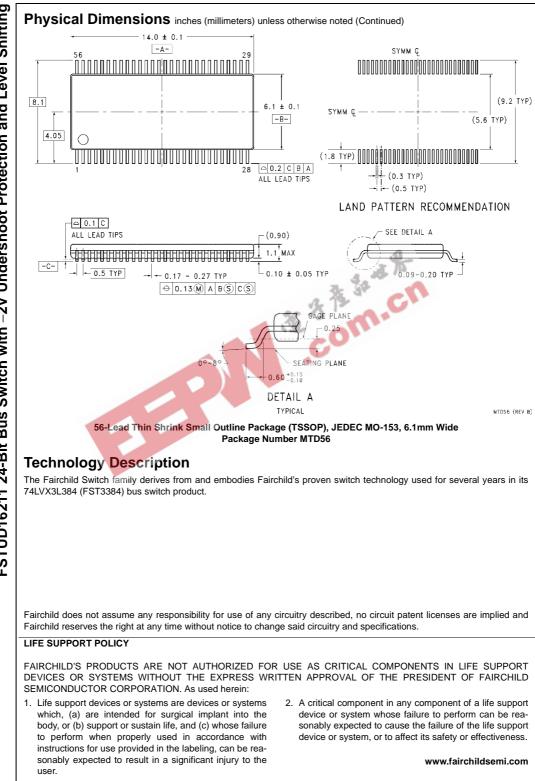




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